ELSEVIER

Thin Solid Films 301 (1997) 253

thin solid films

Author Index of Volume 301

Aegerter, M.A. 236
Aiyer, R.C. 82
Alberts, V. 115
Alsina, M.A. 169
Andrei, A. 71
Ansari, Z.A. 82
Atanassova, E. 1
Atik, M. 236
Attal, J. 134

Barigand, M. 149
Barth, K.-L. 65
Belmonte, T. 35
Belu-Marian, A. 197
Betz, V. 28
Bilello, J.C. 45, 55
Blanco, E. 12
Bonnaud, O. 230
Briand, D. 230
Broll, N. 71
Bruneaux, J. 242
Bucher, E. 115
Byeli, A.V. 183

Cachet, H. 242
Cauneau, S. 230
Chang, L.C. 17
Chen, C.L. 126
Chen, C.S. 7
Chen, H.C. 105
Chieh, W.C. 175
Chitica, N. 71
Choi, W.C. 188
Cornet, A. 71
Cros, B. 134

Devenyi, A. 197
Dongre, M.B. 62
Dragomir, A. 197
Dugnoille, B. 149
Dumont, E. 149

Egea, M.A. 169
Esquivias, L. 12

Fedotov, S.A. 183
Folcher, G. 242
Fortin, B. 230
Froment, M. 242
Fuentes-Gallego, J.J. 12
Fulari, V.J. 62

Gan, Z.-Q. 77
García, M.L. 169
Gavillet, J. 35
Grivas, C. 71
Gyorgy, E. 71

Harima, Y. 95
Hatziapostolou, A. 71
Heberlein, J. 105
Hertz, D. 35
Ho, W.S. 7
Holzapfel, B. 28, 203
Huang, Y.S. 7
Hwang, B.J. 175

Ichimura, K. 162
Imahori, J. 142

Jiang, E.Y. 90
Jiang, Z.-T. 154
Jun, B.-H. 154

Kaemmer, K. 203
Karekar, R.N. 82
Kawai, T. 225
Kazyutchits, N.M. 183
Kim, E.K. 188
Kim, J.-H. 249
Kulkarni, A.K. 17
Kulkarni, H.R. 62
Kwack, D.H. 154

Le Bihan, F. 230
Lee, H.N. 188
Lee, J.S. 154
Lee, M.-S. 188
Li, L.-J. 175
Liao, P.C. 7
Liaw, D.-J. 175
Lin, G.L. 126
Lin, I.N. 126
Lita, A. 71
Liu, Y.G. 90
Lue, J.T. 126
Lunk, A. 65
Lyou, J. 188

Malhotra, S.G. 45, 55
Manaila, R. 197
Marin, G. 71
Matsumoto, K. 95
Matsuzawa, Y. 162
Michel, H. 35
Mihailescu, I.N. 71
Min, S.-K. 188
Mirica, C. 71
Morawski, A. 122
Murakami, M. 142

Ning, Z.-Y. 77
No, K. 154
Nounah, H. 134

Oku, T. 142

Pantelica, D. 71
Pawlicka, A. 236
Petitjean, J.P. 149
Petrascu, M. 71
Pfender, E. 105
Pohoryles, B. 122

Rao, M.R. 217
Rek, Z.U. 45, 55
Ren, Z.-X. 77

Schön, J.H. 115
Schultz, L. 28, 203
Seki, T. 162
Serbanescu, M.D. 197
Shan, J. 23
Shen, M.-R. 77
Shieh, D.T. 175
Shin, S.-C. 211, 249
Sigle, W. 65
Song, H.W. 154
Srinivas, G. 211
Stöckle, D. 65
Stoica, T. 197
Sun, S. 192

Tanase, M. 197
Thielsch, R. 203
Tiong, K.K. 7

Ulmer, J. 65

Valero, J. 169
Valls, O. 169
Varichenko, V.S. 183

Wang, C.D. 90
Wang, H. 77
Wang, Y.-D. 95
Wu, P. 90, 192

Yalisove, S.M. 45, 55
Yamashita, K. 95
Ye, C. 77
Yu, B.G. 154
Yuan, C. 23

Zaitsev, A.M. 183
Zavaliche, F. 197
Zhang, H. 23
Zhu, D. 192

Elsevier Science S.A.

ELSEVIER

Thin Solid Films 301 (1997) 255–258

thin solid films

Subject Index of Volume 301

Aggregation
Spontaneous aggregation of octaalkoxyphthalocyanine metal complexes at an air–water interface, 162
Amorphous materials
Amorphous r.f.-sputtered $Si_{100-x}Ni_x$ thin films with $0 \leq x \leq 15$ at.%: Structural, optical and electrical properties, 197
The preparation, characterization of amorphous Cu–TCNQ film with a low degree of charge-transfer (DCT) and its electric switching properties, 192
Anisotropy
Logarithmic dependence of the surface anisotropy on the low-angle X-ray diffraction intensity in Co-based multilayers, 249
Annealing
In situ TEM observation of metastable phase formed by solid state interdiffusion in a Co–Cu system, 90

$Ba_xSr_{1-x}TiO_3$
Structure-related optical properties of laser-deposited $Ba_xSr_{1-x}TiO_3$ thin films grown on MgO (001) substrates, 203
Boron nitride
Deposition of cubic boron nitride layers — characterisation of substrate–layer interface, 65

Carbides
Synthesis of tungsten carbide thin films by reactive pulsed laser deposition, 71
Carbon
Enhanced diamond nucleation on pretreated silicon substrates, 77
Ceramics
Synthesis of multicolor Nb_2O_5 coatings for electrochromic devices, 236
TEM characterization of plasma-sprayed thermal barrier coatings and ceramic–metal interfaces after hot isostatic pressing, 105
Chemical vapour deposition
Low temperature zirconia thin film synthesis by a chemical vapour deposition process involving $ZrCl_4$ and O_2–H_2–Ar microwave post-discharges. Comparison with a conventional CVD hydrolysis process, 35
Chemical vapour deposition (CVD)
Characterization of unintentionally or lightly doped polysilicon films by improved Hall effect measurements, 230
Dependence of the properties of $(Sr_xTi_{1-x})O_3$ thin films deposited by plasma-enhanced metal–organic chemical vapor deposition on electron cyclotron resonance plasma, 154
Enhanced diamond nucleation on pretreated silicon substrates, 77
Chromium
Electrical and structural characteristics of chromium thin films deposited on glass and alumina substrates, 17
Coatings
Ellipsometric characterization of an AISI 304 stainless steel protective coating, 12
Low temperature zirconia thin film synthesis by a chemical vapour deposition process involving $ZrCl_4$ and O_2–H_2–Ar microwave post-discharges. Comparison with a conventional CVD hydrolysis process, 35
TEM characterization of plasma-sprayed thermal barrier coatings and ceramic–metal interfaces after hot isostatic pressing, 105
Co–Cu multilayer
In situ TEM observation of metastable phase formed by solid state interdiffusion in a Co–Cu system, 90
Compression isotherms
Interaction of flurbiprofen sodium with cornea model monolayers at the air–water interface, 169
Computer simulation
Modification of diamond films by high-energy ion irradiation: "track channelling" and ion charge fluctuation effects, 183
Copper
Diffusion barrier properties of TaC between Si and Cu, 142
Monitoring the deposition of Cu thin film using the double exposure holographic interferometry technique, 62
Cornea membrane model
Interaction of flurbiprofen sodium with cornea model monolayers at the air–water interface, 169
Corrosion
Anodic corrosion of indium tin oxide films induced by the electrochemical oxidation of chlorides, 242

Deposition process
Electropolymerization of pyrrole and 4-(3-Pyrrolyl)butane-sulfonate on Pt substrate: An in situ EQCM study, 175
Monitoring the deposition of Cu thin film using the double exposure holographic interferometry technique, 62
Raman studies of diamond film growth on fuse-silica substrates by a multi-step process, 126
Depth profiling
Analysis of thin film stress measurement techniques, 45
Depth-sensitive strain analysis of a W–Ta–W trilayer, 55
Diamond
Enhanced diamond nucleation on pretreated silicon substrates, 77
Modification of diamond films by high-energy ion irradiation: "track channelling" and ion charge fluctuation effects, 183
Raman studies of diamond film growth on fuse-silica substrates by a multi-step process, 126
Dielectric properties
Dependence of the properties of $(Sr_xTi_{1-x})O_3$ thin films deposited by plasma-enhanced metal–organic chemical vapor deposition on electron cyclotron resonance plasma, 154
Diffusion
Diffusion barrier properties of TaC between Si and Cu, 142

Elastic properties
Qualitative characterization of variation in elastic properties of solid solutions by acoustic microscopy, 134
Electrical properties and measurements
Characterization of unintentionally or lightly doped polysilicon films by improved Hall effect measurements, 230

Electrical and structural characteristics of chromium thin films deposited on glass and alumina substrates, 17
Electrochemistry
Anodic corrosion of indium tin oxide films induced by the electrochemical oxidation of chlorides, 242
Morphology and microstructure of polypyrrole formed by electrochemical polymerization, 23
Optical properties of nickel thin films deposited by electroless plating, 149
Photoelectrolytic micelle disruption method for preparation of free patterns of pigment images, 95
Synthesis of multicolor Nb_2O_5 coatings for electrochromic devices, 236
Electronic devices
The preparation, characterization of amorphous Cu–TCNQ film with a low degree of charge-transfer (DCT) and its electric switching properties, 192
Ellipsometry
Ellipsometric characterization of an AISI 304 stainless steel protective coating, 12
Optical properties of nickel thin films deposited by electroless plating, 149
Epitaxy
$MgO/YBa_2Cu_3O_{7-x}$ multilayer thin films grown on (100) $LaAlO_3$ by pulsed laser deposition, 217

Film structure
Structure-related optical properties of laser-deposited $Ba_xSr_{1-x}TiO_3$ thin films grown on MgO (001) substrates, 203
Film thickness
Photoconductivity — a novel method of evaluation of thin semiconducting film thickness, 122
Flurbiprofen sodium
Interaction of flurbiprofen sodium with cornea model monolayers at the air–water interface, 169
Fourier transform infrared spectroscopy
Deposition of cubic boron nitride layers — characterisation of substrate–layer interface, 65
Molecular orientation in liquid crystals on a photochromic polyion complex LB film by FTIR spectroscopy, 225
The preparation, characterization of amorphous Cu–TCNQ film with a low degree of charge-transfer (DCT) and its electric switching properties, 192

Gallium antimonide
Qualitative characterization of variation in elastic properties of solid solutions by acoustic microscopy, 134
Growth mechanism
Deposition of cubic boron nitride layers — characterisation of substrate–layer interface, 65
Morphology and microstructure of polypyrrole formed by electrochemical polymerization, 23

Hall effect
Characterization of unintentionally or lightly doped polysilicon films by improved Hall effect measurements, 230
Halogens
Anodic corrosion of indium tin oxide films induced by the electrochemical oxidation of chlorides, 242
High energy electron diffraction (RHEED)
In situ reflection high energy electron bombardment analysis of biaxially oriented yttria-stabilized zirconia thin film growth on amorphous substrates, 28

Indium oxide
Anodic corrosion of indium tin oxide films induced by the electrochemical oxidation of chlorides, 242
Interfaces
Diffusion barrier properties of TaC between Si and Cu, 142
Electropolymerization of pyrrole and 4-(3-Pyrrolyl)butane-sulfonate on Pt substrate: An in situ EQCM study, 175
Room temperature reduction of MERIE-like plasma-induced interface states, 1
Ion bombardment
In situ reflection high energy electron bombardment analysis of biaxially oriented yttria-stabilized zirconia thin film growth on amorphous substrates, 28
Ion implantation
Modification of diamond films by high-energy ion irradiation: "track channelling" and ion charge fluctuation effects, 183
Iridium
Characterization of IrO_2 thin films by Raman spectroscopy, 7

Langmuir–Blodgett films
Molecular orientation in liquid crystals on a photochromic polyion complex LB film by FTIR spectroscopy, 225
Laser ablation
In situ reflection high energy electron bombardment analysis of biaxially oriented yttria-stabilized zirconia thin film growth on amorphous substrates, 28
$MgO/YBa_2Cu_3O_{7-x}$ multilayer thin films grown on (100) $LaAlO_3$ by pulsed laser deposition, 217
Synthesis of tungsten carbide thin films by reactive pulsed laser deposition, 71

Magnetic properties and measurements
Logarithmic dependence of the surface anisotropy on the low-angle X-ray diffraction intensity in Co-based multilayers, 249
Magnetic and magneto-optical properties of (Pt/Co/Pt/Ni) multilayers, 211
Magnetic structures
Magnetic and magneto-optical properties of (Pt/Co/Pt/Ni) multilayers, 211
Metal-oxide semiconductors
Room temperature reduction of MERIE-like plasma-induced interface states, 1
Metastable phase
In situ TEM observation of metastable phase formed by solid state interdiffusion in a Co–Cu system, 90
Molybdenum
Analysis of thin film stress measurement techniques, 45
Multilayers
Depth-sensitive strain analysis of a W–Ta–W trilayer, 55
Magnetic and magneto-optical properties of (Pt/Co/Pt/Ni) multilayers, 211
$MgO/YBa_2Cu_3O_{7-x}$ multilayer thin films grown on (100) $LaAlO_3$ by pulsed laser deposition, 217
Molecular orientation in liquid crystals on a photochromic polyion complex LB film by FTIR spectroscopy, 225

Nanostructures
The role of a thin amorphous silicon layer in the fabrication of micro-pored silicon, 188
Nickel
Amorphous r.f.-sputtered $Si_{100-x}Ni_x$ thin films with $0 \leq x \leq 15$ at.%: Structural, optical and electrical properties, 197
Modification of diamond films by high-energy ion irradiation: "track channelling" and ion charge fluctuation effects, 183
Optical properties of nickel thin films deposited by electroless plating, 149
Niobium oxide
Synthesis of multicolor Nb_2O_5 coatings for electrochromic devices, 236

Nucleation
Electropolymerization of pyrrole and 4-(3-Pyrrolyl)butane-sulfonate on Pt substrate: An in situ EQCM study, 175
Enhanced diamond nucleation on pretreated silicon substrates, 77

Optical coatings
Photoelectrolytic micelle disruption method for preparation of free patterns of pigment images, 95
Optical guide
Oxygen sensing properties of V_2O_5 cladded optical glass waveguide, 82
Optical properties
Characterization of IrO_2 thin films by Raman spectroscopy, 7
Optical properties of nickel thin films deposited by electroless plating, 149
Structure-related optical properties of laser-deposited $Ba_xSr_{1-x}TiO_3$ thin films grown on MgO (001) substrates, 203
The role of a thin amorphous silicon layer in the fabrication of micro-pored silicon, 188
Oxides
Characterization of IrO_2 thin films by Raman spectroscopy, 7
Dependence of the properties of $(Sr_xTi_{1-x})O_3$ thin films deposited by plasma-enhanced metal–organic chemical vapor deposition on electron cyclotron resonance plasma, 154
Low temperature zirconia thin film synthesis by a chemical vapour deposition process involving $ZrCl_4$ and O_2–H_2–Ar microwave post-discharges. Comparison with a conventional CVD hydrolysis process, 35
Oxygen sensor
Oxygen sensing properties of V_2O_5 cladded optical glass waveguide, 82

Penetration kinetics
Interaction of flurbiprofen sodium with cornea model monolayers at the air–water interface, 169
Phase transitions
Molecular orientation in liquid crystals on a photochromic polyion complex LB film by FTIR spectroscopy, 225
Morphology and microstructure of polypyrrole formed by electrochemical polymerization, 23
Phthalocyanines
Spontaneous aggregation of octaalkoxyphthalocyanine metal complexes at an air–water interface, 162
Plasma processing and deposition
Dependence of the properties of $(Sr_xTi_{1-x})O_3$ thin films deposited by plasma-enhanced metal–organic chemical vapor deposition on electron cyclotron resonance plasma, 154
Low temperature zirconia thin film synthesis by a chemical vapour deposition process involving $ZrCl_4$ and O_2–H_2–Ar microwave post-discharges. Comparison with a conventional CVD hydrolysis process, 35
Room temperature reduction of MERIE-like plasma-induced interface states, 1
TEM characterization of plasma-sprayed thermal barrier coatings and ceramic–metal interfaces after hot isostatic pressing, 105
Polymers
Electropolymerization of pyrrole and 4-(3-Pyrrolyl)butane-sulfonate on Pt substrate: An in situ EQCM study, 175
Morphology and microstructure of polypyrrole formed by electrochemical polymerization, 23
Pulsed laser deposition
Structure-related optical properties of laser-deposited $Ba_xSr_{1-x}TiO_3$ thin films grown on MgO (001) substrates, 203
Pyrolysis
Photoelectrolytic micelle disruption method for preparation of free patterns of pigment images, 95

Raman scattering
Characterization of IrO_2 thin films by Raman spectroscopy, 7
Raman studies of diamond film growth on fuse-silica substrates by a multi-step process, 126
Reactive sputtering
Characterization of IrO_2 thin films by Raman spectroscopy, 7
Resistivity
Electrical and structural characteristics of chromium thin films deposited on glass and alumina substrates, 17

Scanning electron microscopy
Raman studies of diamond film growth on fuse-silica substrates by a multi-step process, 126
Structural and optical characterization of polycrystalline $CuInSe_2$, 115
The preparation, characterization of amorphous Cu–TCNQ film with a low degree of charge-transfer (DCT) and its electric switching properties, 192
The role of a thin amorphous silicon layer in the fabrication of micro-pored silicon, 188
Semiconductors
Photoconductivity — a novel method of evaluation of thin semiconducting film thickness, 122
Silicon
Amorphous r.f.-sputtered $Si_{100-x}Ni_x$ thin films with $0 \leq x \leq 15$ at.%: Structural, optical and electrical properties, 197
Characterization of unintentionally or lightly doped polysilicon films by improved Hall effect measurements, 230
Diffusion barrier properties of TaC between Si and Cu, 142
The role of a thin amorphous silicon layer in the fabrication of micro-pored silicon, 188
Sintering
Ellipsometric characterization of an AISI 304 stainless steel protective coating, 12
Solar cells
Structural and optical characterization of polycrystalline $CuInSe_2$, 115
Solid-state interdiffusion
In situ TEM observation of metastable phase formed by solid state interdiffusion in a Co–Cu system, 90
Steel
Ellipsometric characterization of an AISI 304 stainless steel protective coating, 12
Qualitative characterization of variation in elastic properties of solid solutions by acoustic microscopy, 134
Stress
Analysis of thin film stress measurement techniques, 45
Structural properties
Electrical and structural characteristics of chromium thin films deposited on glass and alumina substrates, 17
Superconductivity
$MgO/YBa_2Cu_3O_{7-x}$ multilayer thin films grown on (100) $LaAlO_3$ by pulsed laser deposition, 217
Surface and interface states
Logarithmic dependence of the surface anisotropy on the low-angle X-ray diffraction intensity in Co-based multilayers, 249
Surface composition
Synthesis of tungsten carbide thin films by reactive pulsed laser deposition, 71
Surface defects
Monitoring the deposition of Cu thin film using the double exposure holographic interferometry technique, 62

Thin films
Structure-related optical properties of laser-deposited $Ba_xSr_{1-x}TiO_3$ thin films grown on MgO (001) substrates, 203
Transmission electron microscopy (TEM)
TEM characterization of plasma-sprayed thermal barrier coatings and ceramic–metal interfaces after hot isostatic pressing, 105

Transmission electron microscopy
Deposition of cubic boron nitride layers — characterisation of substrate–layer interface, 65
Structural and optical characterization of polycrystalline $CuInSe_2$, 115
Tungsten
Synthesis of tungsten carbide thin films by reactive pulsed laser deposition, 71

V_2O_5 cladding
Oxygen sensing properties of V_2O_5 cladded optical glass waveguide, 82

X-ray diffraction
Analysis of thin film stress measurement techniques, 45
Depth-sensitive strain analysis of a W–Ta–W trilayer, 55
Logarithmic dependence of the surface anisotropy on the low-angle X-ray diffraction intensity in Co-based multilayers, 249
Structural and optical characterization of polycrystalline $CuInSe_2$, 115

Zinc oxide
Photoelectrolytic micelle disruption method for preparation of free patterns of pigment images, 95